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Details

Product Status	Obsolete
Core Processor	8051
Core Size	8-Bit
Speed	50MHz
Connectivity	EBI/EMI, I ² C, LINbus, SPI, UART/USART, USB
Peripherals	CapSense, DMA, LCD, POR, PWM, WDT
Number of I/O	62
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	1K x 8
RAM Size	4K x 8
Voltage - Supply (Vcc/Vdd)	1.71V ~ 5.5V
Data Converters	A/D 16x12b; D/A 2x8b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	100-LQFP
Supplier Device Package	100-TQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/cy8c3445axi-108

4.3.1.2 Logical Instructions

The logical instructions perform Boolean operations such as AND, OR, XOR on bytes, rotate of accumulator contents, and swap of nibbles in an accumulator. The Boolean operations on the bytes are performed on the bit-by-bit basis. [Table 4-2](#) shows the list of logical instructions and their description.

Table 4-2. Logical Instructions

Mnemonic	Description	Bytes	Cycles
ANL A,Rn	AND register to accumulator	1	1
ANL A,Direct	AND direct byte to accumulator	2	2
ANL A,@Ri	AND indirect RAM to accumulator	1	2
ANL A,#data	AND immediate data to accumulator	2	2
ANL Direct, A	AND accumulator to direct byte	2	3
ANL Direct, #data	AND immediate data to direct byte	3	3
ORL A,Rn	OR register to accumulator	1	1
ORL A,Direct	OR direct byte to accumulator	2	2
ORL A,@Ri	OR indirect RAM to accumulator	1	2
ORL A,#data	OR immediate data to accumulator	2	2
ORL Direct, A	OR accumulator to direct byte	2	3
ORL Direct, #data	OR immediate data to direct byte	3	3
XRL A,Rn	XOR register to accumulator	1	1
XRL A,Direct	XOR direct byte to accumulator	2	2
XRL A,@Ri	XOR indirect RAM to accumulator	1	2
XRL A,#data	XOR immediate data to accumulator	2	2
XRL Direct, A	XOR accumulator to direct byte	2	3
XRL Direct, #data	XOR immediate data to direct byte	3	3
CLR A	Clear accumulator	1	1
CPL A	Complement accumulator	1	1
RL A	Rotate accumulator left	1	1
RLC A	Rotate accumulator left through carry	1	1
RR A	Rotate accumulator right	1	1
RRC A	Rotate accumulator right through carry	1	1
SWAP A	Swap nibbles within accumulator	1	1

Table 4-4. Boolean Instructions

Mnemonic	Description	Bytes	Cycles
CLR C	Clear carry	1	1
CLR bit	Clear direct bit	2	3
SETB C	Set carry	1	1
SETB bit	Set direct bit	2	3
CPL C	Complement carry	1	1
CPL bit	Complement direct bit	2	3
ANL C, bit	AND direct bit to carry	2	2
ANL C, /bit	AND complement of direct bit to carry	2	2
ORL C, bit	OR direct bit to carry	2	2
ORL C, /bit	OR complement of direct bit to carry	2	2
MOV C, bit	Move direct bit to carry	2	2
MOV bit, C	Move carry to direct bit	2	3
JC rel	Jump if carry is set	2	3
JNC rel	Jump if no carry is set	2	3
JB bit, rel	Jump if direct bit is set	3	5
JNB bit, rel	Jump if direct bit is not set	3	5
JBC bit, rel	Jump if direct bit is set and clear bit	3	5

4.3.1.5 Program Branching Instructions

The 8051 supports a set of conditional and unconditional jump instructions that help to modify the program execution flow. [Table 4-5](#) shows the list of jump instructions.

Table 4-5. Jump Instructions

Mnemonic	Description	Bytes	Cycles
ACALL addr11	Absolute subroutine call	2	4
LCALL addr16	Long subroutine call	3	4
RET	Return from subroutine	1	4
RETI	Return from interrupt	1	4
AJMP addr11	Absolute jump	2	3
LJMP addr16	Long jump	3	4
SJMP rel	Short jump (relative address)	2	3
JMP @A + DPTR	Jump indirect relative to DPTR	1	5
JZ rel	Jump if accumulator is zero	2	4
JNZ rel	Jump if accumulator is nonzero	2	4
CJNE A, Direct, rel	Compare direct byte to accumulator and jump if not equal	3	5
CJNE A, #data, rel	Compare immediate data to accumulator and jump if not equal	3	4
CJNE Rn, #data, rel	Compare immediate data to register and jump if not equal	3	4
CJNE @Ri, #data, rel	Compare immediate data to indirect RAM and jump if not equal	3	5
DJNZ Rn, rel	Decrement register and jump if not zero	2	4
DJNZ Direct, rel	Decrement direct byte and jump if not zero	3	5
NOP	No operation	1	1

5.7 Memory Map

The CY8C34 8051 memory map is very similar to the MCS-51 memory map.

5.7.1 Code Space

The CY8C34 8051 code space is 64 KB. Only main flash exists in this space. See the “Flash Program Memory” section on page 22.

5.7.2 Internal Data Space

The CY8C34 8051 internal data space is 384 bytes, compressed within a 256-byte space. This space consists of 256 bytes of RAM (in addition to the SRAM mentioned in [Static RAM](#) on page 22) and a 128-byte space for Special Function Registers (SFRs). See [Figure 5-2](#). The lowest 32 bytes are used for 4 banks of registers R0-R7. The next 16 bytes are bit-addressable.

Figure 5-2. 8051 Internal Data Space

0x00 0x1F	4 Banks, R0-R7 Each	
0x20 0x2F	Bit-Addressable Area	
0x30 0x7F	Lower Core RAM Shared with Stack Space (direct and indirect addressing)	
0x80 0xFF	Upper Core RAM Shared with Stack Space (indirect addressing)	SFR Special Function Registers (direct addressing)

In addition to the register or bit address modes used with the lower 48 bytes, the lower 128 bytes can be accessed with direct or indirect addressing. With direct addressing mode, the upper 128 bytes map to the SFRs. With indirect addressing mode, the upper 128 bytes map to RAM. Stack operations use indirect addressing; the 8051 stack space is 256 bytes. See the “Addressing Modes” section on page 12

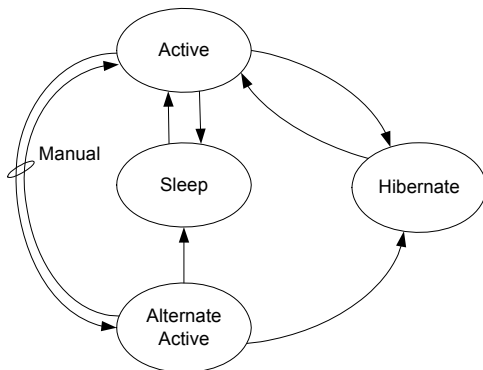
5.7.3 SFRs

The Special Function Register (SFR) space provides access to frequently accessed registers. The memory map for the SFR memory space is shown in [Table 5-4](#).

Table 5-4. SFR Map

Address	0/8	1/9	2/A	3/B	4/C	5/D	6/E	7/F
0xF8	SFRPRT15DR	SFRPRT15PS	SFRPRT15SEL					
0xF0	B		SFRPRT12SEL					
0xE8	SFRPRT12DR	SFRPRT12PS	MXAX					
0xE0	ACC							
0xD8	SFRPRT6DR	SFRPRT6PS	SFRPRT6SEL					
0xD0	PSW							
0xC8	SFRPRT5DR	SFRPRT5PS	SFRPRT5SEL					
0xC0	SFRPRT4DR	SFRPRT4PS	SFRPRT4SEL					
0xB8								
0xB0	SFRPRT3DR	SFRPRT3PS	SFRPRT3SEL					
0xA8	IE							
0xA0	P2AX		SFRPRT1SEL					
0x98	SFRPRT2DR	SFRPRT2PS	SFRPRT2SEL					
0x90	SFRPRT1DR	SFRPRT1PS		DPX0		DPX1		
0x88		SFRPRT0PS	SFRPRT0SEL					
0x80	SFRPRT0DR	SP	DPL0	DPH0	DPL1	DPH1	DPS	

Figure 6-5. Power Mode Transitions



6.2.1.1 Active Mode

Active mode is the primary operating mode of the device. When in active mode, the active configuration template bits control which available resources are enabled or disabled. When a resource is disabled, the digital clocks are gated, analog bias currents are disabled, and leakage currents are reduced as appropriate. User firmware can dynamically control subsystem power by setting and clearing bits in the active configuration template. The CPU can disable itself, in which case the CPU is automatically reenabled at the next wakeup event.

When a wakeup event occurs, the global mode is always returned to active, and the CPU is automatically enabled, regardless of its template settings. Active mode is the default global power mode upon boot.

6.2.1.2 Alternate Active Mode

Alternate Active mode is very similar to Active mode. In alternate active mode, fewer subsystems are enabled, to reduce power consumption. One possible configuration is to turn off the CPU and flash, and run peripherals at full speed.

6.2.1.3 Sleep Mode

Sleep mode reduces power consumption when a resume time of 15 μ s is acceptable. The wake time is used to ensure that the regulator outputs are stable enough to directly enter active mode.

6.2.1.4 Hibernate Mode

In hibernate mode nearly all of the internal functions are disabled. Internal voltages are reduced to the minimal level to keep vital systems alive. Configuration state is preserved in hibernate mode and SRAM memory is retained. GPIOs configured as digital outputs maintain their previous values and external GPIO pin interrupt settings are preserved. The device can only return from hibernate mode in response to an external I/O interrupt. The resume time from hibernate mode is less than 100 μ s.

To achieve an extremely low current, the hibernate regulator has limited capacity. This limits the frequency of any signal present on the input pins - no GPIO should toggle at a rate greater than 10 kHz while in hibernate mode. If pins must be toggled at a high rate while in a low power mode, use sleep mode instead.

6.2.1.5 Wakeup Events

Wakeup events are configurable and can come from an interrupt or device reset. A wakeup event restores the system to active mode. Firmware enabled interrupt sources include internally generated interrupts, power supervisor, central timewheel, and I/O interrupts. Internal interrupt sources can come from a variety of peripherals, such as analog comparators and UDBs. The central timewheel provides periodic interrupts to allow the system to wake up, poll peripherals, or perform real-time functions. Reset event sources include the external reset I/O pin (XRES), WDT, and Precision Reset (PRES).

6.2.2 Boost Converter

Applications that use a supply voltage of less than 1.71 V, such as solar panels or single cell battery supplies, may use the on-chip boost converter to generate a minimum of 1.8 V supply voltage. The boost converter may also be used in any system that requires a higher operating voltage than the supply provides such as driving 5.0 V LCD glass in a 3.3 V system. With the addition of an inductor, Schottky diode, and capacitors, it produces a selectable output voltage sourcing enough current to operate the PSoC and other on-board components.

The boost converter accepts an input voltage V_{BAT} from 0.5 V to 3.6 V, and can start up with V_{BAT} as low as 0.5 V. The converter provides a user configurable output voltage of 1.8 to 5.0 V (V_{OUT}) in 100 mV increments. V_{BAT} is typically less than V_{OUT} ; if V_{BAT} is greater than or equal to V_{OUT} , then V_{OUT} will be slightly less than V_{BAT} due to resistive losses in the boost converter. The block can deliver up to 50 mA (I_{BOOST}) depending on configuration to both the PSoC device and external components. The sum of all current sinks in the design including the PSoC device, PSoC I/O pin loads, and external component loads must be less than the I_{BOOST} specified maximum current.

Four pins are associated with the boost converter: VBAT, VSSB, VBOOST, and IND. The boosted output voltage is sensed at the VBOOST pin and must be connected directly to the chip's supply inputs; VDDA, VDDD, and VDDIO if used to power the PSoC device.

The boost converter requires four components in addition to those required in a non-boost design, as shown in Figure 6-6 on page 33. A 22 μ F capacitor (CBAT) is required close to the VBAT pin to provide local bulk storage of the battery voltage and provide regulator stability. A diode between the battery and VBAT pin should not be used for reverse polarity protection because the diodes forward voltage drop reduces the V_{BAT} voltage. Between the VBAT and IND pins, an inductor of 4.7 μ H, 10 μ H, or 22 μ H is required. The inductor value can be optimized to increase the boost converter efficiency based on input voltage, output voltage, temperature, and current. Inductor size is determined by following the design guidance in this chapter and electrical specifications. The inductor must be placed within 1 cm of the VBAT and IND pins and have a minimum saturation current of 750 mA. Between the IND and VBOOST pins, place a Schottky diode within 1 cm of the pins. The Schottky diode shall have a forward current rating of at least 1.0 A and a reverse voltage of at least 20 V. Connect a 22- μ F bulk capacitor (CBOOST) close to VBOOST to provide regulator output stability. It is important to sum the total capacitance connected to the VBOOST pin and ensure the maximum C_{BOOST} specification is not exceeded. All capacitors must be rated for a minimum of 10 V to minimize capacitive losses due to voltage de-rating.

7.7 Timers, Counters, and PWMs

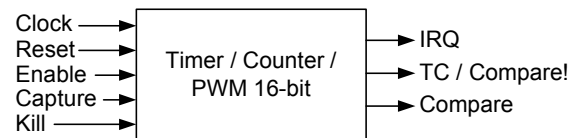
The Timer/Counter/PWM peripheral is a 16-bit dedicated peripheral providing three of the most common embedded peripheral features. As almost all embedded systems use some combination of timers, counters, and PWMs. Four of them have been included on this PSoC device family. Additional and more advanced functionality timers, counters, and PWMs can also be instantiated in Universal Digital Blocks (UDBs) as required. PSoC Creator allows you to choose the timer, counter, and PWM features that they require. The tool set utilizes the most optimal resources available.

The Timer/Counter/PWM peripheral can select from multiple clock sources, with input and output signals connected through the DSI routing. DSI routing allows input and output connections to any device pin and any internal digital signal accessible through the DSI. Each of the four instances has a compare output, terminal count output (optional complementary compare output), and programmable interrupt request line. The Timer/Counter/PWMs are configurable as free running, one shot, or Enable input controlled. The peripheral has timer reset and capture inputs, and a kill input for control of the comparator outputs. The peripheral supports full 16-bit capture.

Timer/Counter/PWM features include:

- 16-bit Timer/Counter/PWM (down count only)
- Selectable clock source
- PWM comparator (configurable for LT, LTE, EQ, GTE, GT)
- Period reload on start, reset, and terminal count
- Interrupt on terminal count, compare true, or capture
- Dynamic counter reads
- Timer capture mode
- Count while enable signal is asserted mode
- Free run mode
- One Shot mode (stop at end of period)
- Complementary PWM outputs with deadband
- PWM output kill

Figure 7-17. Timer/Counter/PWM



Analog local buses (abus) are routing resources located within the analog subsystem and are used to route signals between different analog blocks. There are eight abus routes in CY8C34, four in the left half (abusl [0:3]) and four in the right half (abusr [0:3]) as shown in Figure 8-2. Using the abus saves the analog globals and analog mux buses from being used for interconnecting the analog blocks.

Multiplexers and switches exist on the various buses to direct signals into and out of the analog blocks. A multiplexer can have only one connection on at a time, whereas a switch can have multiple connections on simultaneously. In Figure 8-2, multiplexers are indicated by grayed ovals and switches are indicated by transparent ovals.

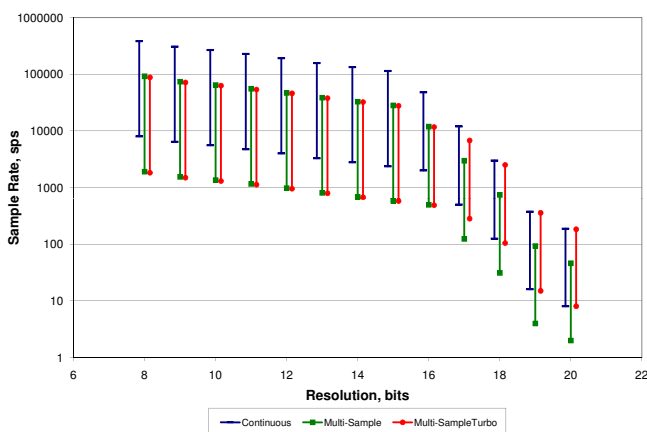
8.2 Delta-sigma ADC

The CY8C34 device contains one delta-sigma ADC. This ADC offers differential input, high resolution and excellent linearity, making it a good ADC choice for measurement applications. The converter can be configured to output 12-bit resolution at data rates of up to 192 ksp/s. At a fixed clock rate, resolution can be traded for faster data rates as shown in Table 8-1 and Figure 8-3.

Table 8-1. Delta-sigma ADC Performance

Bits	Maximum Sample Rate (sp/s)	SINAD (dB)
12	192 k	66
8	384 k	43

Figure 8-3. Delta-sigma ADC Sample Rates, Range = ±1.024 V

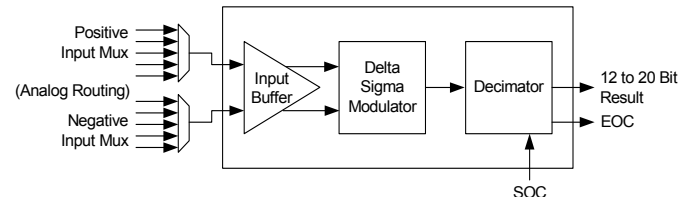


8.2.1 Functional Description

The ADC connects and configures three basic components, input buffer, delta-sigma modulator, and decimator. The basic block diagram is shown in Figure 8-4. The signal from the input muxes is delivered to the delta-sigma modulator either directly or through the input buffer. The delta-sigma modulator performs the actual analog to digital conversion. The modulator over-samples the input and generates a serial data stream output. This high speed data stream is not useful for most applications without some type of post processing, and so is passed to the decimator through the Analog Interface block. The decimator converts the

high speed serial data stream into parallel ADC results. The modulator/decimator frequency response is $[(\sin x)/x]^4$.

Figure 8-4. Delta-sigma ADC Block Diagram



Resolution and sample rate are controlled by the Decimator. Data is pipelined in the decimator; the output is a function of the last four samples. When the input multiplexer is switched, the output data is not valid until after the fourth sample after the switch.

8.2.2 Operational Modes

The ADC can be configured by the user to operate in one of four modes: Single Sample, Multi Sample, Continuous, or Multi Sample (Turbo). All four modes are started by either a write to the start bit in a control register or an assertion of the Start of Conversion (SoC) signal. When the conversion is complete, a status bit is set and the output signal End of Conversion (EoC) asserts high and remains high until the value is read by either the DMA controller or the CPU.

8.2.2.1 Single Sample

In Single Sample mode, the ADC performs one sample conversion on a trigger. In this mode, the ADC stays in standby state waiting for the SoC signal to be asserted. When SoC is signaled the ADC performs four successive conversions. The first three conversions prime the decimator. The ADC result is valid and available after the fourth conversion, at which time the EoC signal is generated. To detect the end of conversion, the system may poll a control register for status or configure the external EoC signal to generate an interrupt or invoke a DMA request. When the transfer is done the ADC reenters the standby state where it stays until another SoC event.

8.2.2.2 Continuous

Continuous sample mode is used to take multiple successive samples of a single input signal. Multiplexing multiple inputs should not be done with this mode. There is a latency of three conversion times before the first conversion result is available. This is the time required to prime the decimator. After the first result, successive conversions are available at the selected sample rate.

8.2.2.3 Multi Sample

Multi sample mode is similar to continuous mode except that the ADC is reset between samples. This mode is useful when the input is switched between multiple signals. The decimator is re-primed between each sample so that previous samples do not affect the current conversion. Upon completion of a sample, the next sample is automatically initiated. The results can be transferred using either firmware polling, interrupt, or DMA.

More information on output formats is provided in the Technical Reference Manual.

8.3.2 LUT

The CY8C34 family of devices contains four LUTs. The LUT is a two input, one output lookup table that is driven by any one or two of the comparators in the chip. The output of any LUT is routed to the digital system interface of the UDB array. From the digital system interface of the UDB array, these signals can be connected to UDBs, DMA controller, I/O, or the interrupt controller.

The LUT control word written to a register sets the logic function on the output. The available LUT functions and the associated control word is shown in Table 8-2.

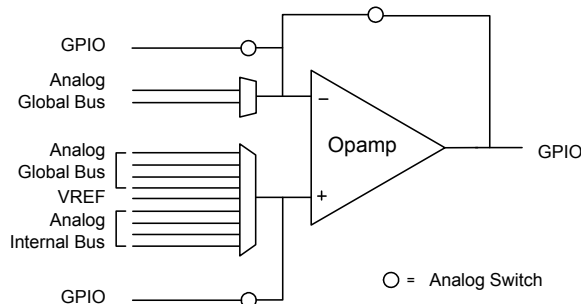
Table 8-2. LUT Function vs. Program Word and Inputs

Control Word	Output (A and B are LUT inputs)
0000b	FALSE ('0')
0001b	A AND B
0010b	A AND (NOT B)
0011b	A
0100b	(NOT A) AND B
0101b	B
0110b	A XOR B
0111b	A OR B
1000b	A NOR B
1001b	A XNOR B
1010b	NOT B
1011b	A OR (NOT B)
1100b	NOT A
1101b	(NOT A) OR B
1110b	A NAND B
1111b	TRUE ('1')

8.4 Opamps

The CY8C34 family of devices contains two general purpose opamps in a device.

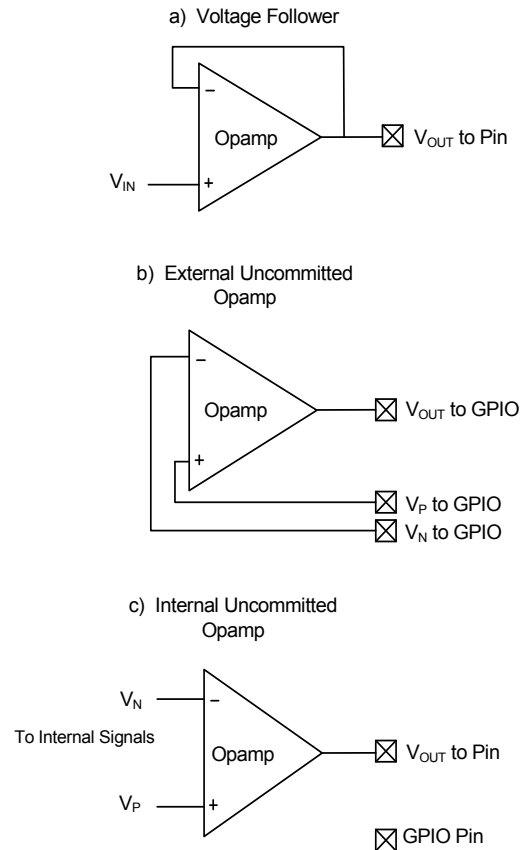
Figure 8-6. Opamp



The opamp is uncommitted and can be configured as a gain stage or voltage follower, or output buffer on external or internal signals.

See Figure 8-7. In any configuration, the input and output signals can all be connected to the internal global signals and monitored with an ADC, or comparator. The configurations are implemented with switches between the signals and GPIO pins.

Figure 8-7. Opamp Configurations



The opamp has three speed modes, slow, medium, and fast. The slow mode consumes the least amount of quiescent power and the fast mode consumes the most power. The inputs are able to swing rail-to-rail. The output swing is capable of rail-to-rail operation at low current output, within 50 mV of the rails. When driving high current loads (about 25 mA) the output voltage may only get within 500 mV of the rails.

8.5 Programmable SC/CT Blocks

The CY8C34 family of devices contains two switched capacitor/continuous time (SC/CT) blocks in a device. Each switched capacitor/continuous time block is built around a single rail-to-rail high bandwidth opamp.

Switched capacitor is a circuit design technique that uses capacitors plus switches instead of resistors to create analog functions. These circuits work by moving charge between capacitors by opening and closing different switches. Nonoverlapping in phase clock signals control the switches, so that not all switches are ON simultaneously.

11.2 Device Level Specifications

Specifications are valid for $-40\text{ }^{\circ}\text{C} \leq T_A \leq 85\text{ }^{\circ}\text{C}$ and $T_J \leq 100\text{ }^{\circ}\text{C}$, except where noted. Specifications are valid for 1.71 V to 5.5 V, except where noted.

11.2.1 Device Level Specifications

Table 11-2. DC Specifications

Parameter	Description	Conditions	Min	Typ ^[25]	Max	Units	
V _{DDA}	Analog supply voltage and input to analog core regulator	Analog core regulator enabled	1.8	–	5.5	V	
V _{DDA}	Analog supply voltage, analog regulator bypassed	Analog core regulator disabled	1.71	1.8	1.89	V	
V _{DDD}	Digital supply voltage relative to V _{SSD}	Digital core regulator enabled	1.8 –	– –	V _{DDA} ^[21] V _{DDA} + 0.1 ^[27]	V	
V _{DDD}	Digital supply voltage, digital regulator bypassed	Digital core regulator disabled	1.71	1.8	1.89	V	
V _{DDIO} ^[22]	I/O supply voltage relative to V _{SSIO}		1.71 –	– –	V _{DDA} ^[21] V _{DDA} + 0.1 ^[27]	V	
V _{CCA}	Direct analog core voltage input (Analog regulator bypass)	Analog core regulator disabled	1.71	1.8	1.89	V	
V _{CCD}	Direct digital core voltage input (Digital regulator bypass)	Digital core regulator disabled	1.71	1.8	1.89	V	
I _{DD} ^[23, 24]	Active Mode						
	Only IMO and CPU clock enabled. CPU executing simple loop from instruction buffer.	V _{DDX} = 2.7 V – 5.5 V; F _{CPU} = 6 MHz ^[26]	T = –40 °C	–	1.2	2.9	mA
			T = 25 °C	–	1.2	3.1	
			T = 85 °C	–	4.9	7.7	
	IMO enabled, bus clock and CPU clock enabled. CPU executing program from flash.	V _{DDX} = 2.7 V – 5.5 V; F _{CPU} = 3 MHz ^[26]	T = –40 °C	–	1.3	2.9	
			T = 25 °C	–	1.6	3.2	
			T = 85 °C	–	4.8	7.5	
		V _{DDX} = 2.7 V – 5.5 V; F _{CPU} = 6 MHz	T = –40 °C	–	2.1	3.7	
			T = 25 °C	–	2.3	3.9	
			T = 85 °C	–	5.6	8.5	
		V _{DDX} = 2.7 V – 5.5 V; F _{CPU} = 12 MHz ^[26]	T = –40 °C	–	3.5	5.2	
			T = 25 °C	–	3.8	5.5	
			T = 85 °C	–	7.1	9.8	
	V _{DDX} = 2.7 V – 5.5 V; F _{CPU} = 24 MHz ^[26]	T = –40 °C	–	6.3	8.1		
		T = 25 °C	–	6.6	8.3		
		T = 85 °C	–	10	13		
	V _{DDX} = 2.7 V – 5.5 V; F _{CPU} = 48 MHz ^[26]	T = –40 °C	–	11.5	13.5		
		T = 25 °C	–	12	14		
T = 85 °C		–	15.5	18.5			

Notes

21. The power supplies can be brought up in any sequence however once stable V_{DDA} must be greater than or equal to all other supplies.
22. The V_{DDIO} supply voltage must be greater than the maximum voltage on the associated GPIO pins. Maximum voltage on GPIO pin $\leq V_{DDIO} \leq V_{DDA}$.
23. Total current for all power domains: digital (I_{DDD}), analog (I_{DDA}), and I/Os ($I_{DDIO0, 1, 2, 3}$). Boost not included. All I/Os floating.
24. The current consumption of additional peripherals that are implemented only in programmed logic blocks can be found in their respective datasheets, available in PSoC Creator, the integrated design environment. To estimate total current, find the CPU current at the frequency of interest and add peripheral currents for your particular system from the device datasheet and component datasheets.
25. $V_{DDX} = 3.3\text{ V}$.
26. Based on device characterization (Not Production tested).
27. Guaranteed by design, not production tested.

11.3.3 Inductive Boost Regulator

Unless otherwise specified, operating conditions are: $V_{BAT} = 0.5\text{ V} - 3.6\text{ V}$, $V_{OUT} = 1.8\text{ V} - 5.0\text{ V}$, $I_{OUT} = 0\text{ mA} - 50\text{ mA}$, $L_{BOOST} = 4.7\text{ }\mu\text{H} - 22\text{ }\mu\text{H}$, $C_{BOOST} = 22\text{ }\mu\text{F} \parallel 3 \times 1.0\text{ }\mu\text{F} \parallel 3 \times 0.1\text{ }\mu\text{F}$, $C_{BAT} = 22\text{ }\mu\text{F}$, $I_F = 1.0\text{ A}$. Unless otherwise specified, all charts and graphs show typical values.

Table 11-6. Inductive Boost Regulator DC Specifications

Parameter	Description	Conditions		Min	Typ	Max	Units
V _{OUT}	Boost output voltage ^[34]	vsel = 1.8 V in register BOOST_CR0		1.71	1.8	1.89	V
		vsel = 1.9 V in register BOOST_CR0		1.81	1.90	2.00	V
		vsel = 2.0 V in register BOOST_CR0		1.90	2.00	2.10	V
		vsel = 2.4 V in register BOOST_CR0		2.16	2.40	2.64	V
		vsel = 2.7 V in register BOOST_CR0		2.43	2.70	2.97	V
		vsel = 3.0 V in register BOOST_CR0		2.70	3.00	3.30	V
		vsel = 3.3 V in register BOOST_CR0		2.97	3.30	3.63	V
		vsel = 3.6 V in register BOOST_CR0		3.24	3.60	3.96	V
		vsel = 5.0 V in register BOOST_CR0		4.50	5.00	5.50	V
V _{BAT}	Input voltage to boost ^[35]	I _{OUT} = 0 mA–5 mA	vsel = 1.8 V–2.0 V, T _A = 0 °C–70 °C	0.5	–	0.8	V
		I _{OUT} = 0 mA–15 mA	vsel = 1.8 V–5.0 V ^[36] , T _A = –10 °C–85 °C	1.6	–	3.6	V
		I _{OUT} = 0 mA–25 mA	vsel = 1.8 V–2.7 V, T _A = –10 °C–85 °C	0.8	–	1.6	V
		I _{OUT} = 0 mA–50 mA	vsel = 1.8 V–3.3 V ^[36] , T _A = –40 °C–85 °C	1.8	–	2.5	V
			vsel = 1.8 V–3.3 V ^[36] , T _A = –10 °C–85 °C	1.3	–	2.5	V
			vsel = 2.5 V–5.0 V ^[36] , T _A = –10 °C–85 °C	2.5	–	3.6	V
		I _{OUT}	Output current	T _A = 0 °C–70 °C	V _{BAT} = 0.5 V–0.8 V	0	–
T _A = –10 °C–85 °C	V _{BAT} = 1.6 V–3.6 V			0	–	15	mA
	V _{BAT} = 0.8 V–1.6 V			0	–	25	mA
	V _{BAT} = 1.3 V–2.5 V			0	–	50	mA
	V _{BAT} = 2.5 V–3.6 V			0	–	50	mA
T _A = –40 °C–85 °C	V _{BAT} = 1.8 V–2.5 V			0	–	50	mA
I _{LPK}	Inductor peak current					–	–
I _Q	Quiescent current	Boost active mode		–	250	–	μA
		Boost sleep mode, I _{OUT} < 1 μA		–	25	–	μA
Reg _{LOAD}	Load regulation			–	–	10	%
Reg _{LINE}	Line regulation			–	–	10	%

Notes

34. Listed v_{sel} options are characterized. Additional v_{sel} options are valid and guaranteed by design.

35. The boost will start at all valid V_{BAT} conditions including down to $V_{BAT} = 0.5\text{ V}$.

36. If V_{BAT} is greater than or equal to V_{OUT} boost setting, then V_{OUT} will be less than V_{BAT} due to resistive losses in the boost circuit.

Figure 11-22. USBIO Output High Voltage and Current, GPIO Mode

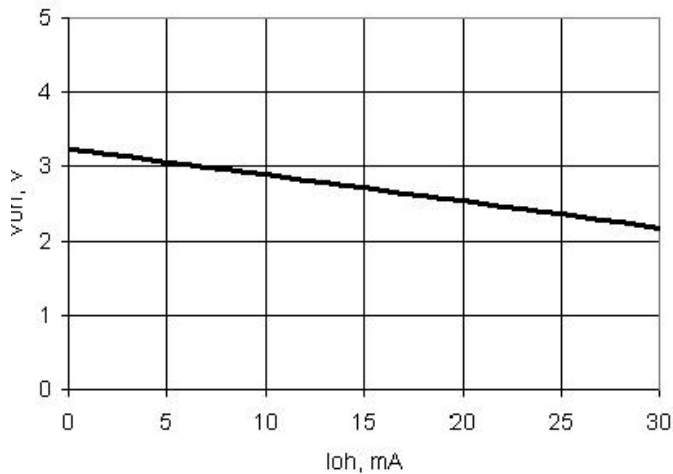


Figure 11-23. USBIO Output Low Voltage and Current, GPIO Mode

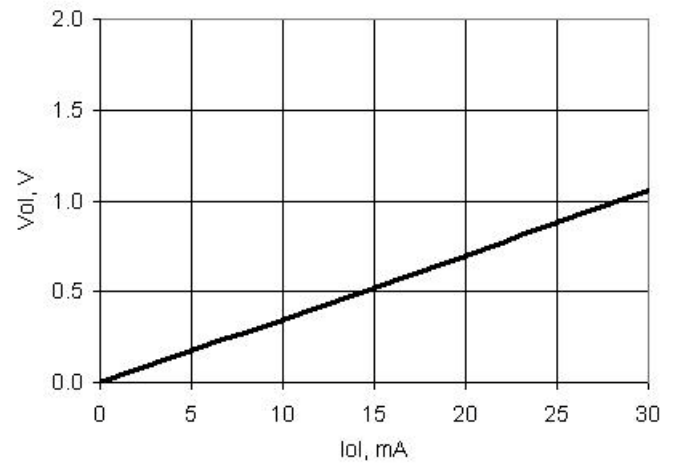


Table 11-15. USBIO AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
Td _{rate}	Full-speed data rate average bit rate		12 – 0.25%	12	12 + 0.25%	MHz
Tj _{r1}	Receiver data jitter tolerance to next transition		–8	–	8	ns
Tj _{r2}	Receiver data jitter tolerance to pair transition		–5	–	5	ns
Td _{j1}	Driver differential jitter to next transition		–3.5	–	3.5	ns
Td _{j2}	Driver differential jitter to pair transition		–4	–	4	ns
Tf _{deop}	Source jitter for differential transition to SE0 transition		–2	–	5	ns
Tf _{eo_{pt}}	Source SE0 interval of EOP		160	–	175	ns
Tf _{eo_{pr}}	Receiver SE0 interval of EOP		82	–	–	ns
Tf _{st}	Width of SE0 interval during differential transition		–	–	14	ns
F _{gpio_out}	GPIO mode output operating frequency	3 V ≤ V _{DD} ≤ 5.5 V	–	–	20	MHz
		V _{DD} = 1.71 V	–	–	6	MHz
Tr _{gpio}	Rise time, GPIO mode, 10%/90% V _{DD}	V _{DD} > 3 V, 25 pF load	–	–	12	ns
		V _{DD} = 1.71 V, 25 pF load	–	–	40	ns
Tf _{gpio}	Fall time, GPIO mode, 90%/10% V _{DD}	V _{DD} > 3 V, 25 pF load	–	–	12	ns
		V _{DD} = 1.71 V, 25 pF load	–	–	40	ns

**Figure 11-24. USBIO Output Rise and Fall Times, GPIO Mode,
 $V_{DD} = 3.3\text{ V}$, 25 pF Load**

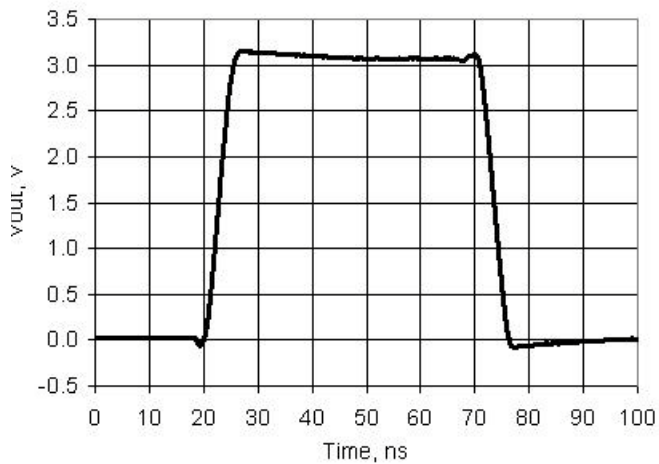


Table 11-16. USB Driver AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
Tr	Transition rise time		–	–	20	ns
Tf	Transition fall time		–	–	20	ns
TR	Rise/fall time matching	V_{USB_5} , $V_{USB_3.3}$, see USB DC Specifications on page 107	90%	–	111%	
Vcrs	Output signal crossover voltage		1.3	–	2	V

11.5.6 Current Digital-to-analog Converter (IDAC)

All specifications are based on use of the low-resistance IDAC output pins (see [Pin Descriptions](#) on page 11 for details). See the IDAC component data sheet in PSoC Creator for full electrical specifications and APIs.

Unless otherwise specified, all charts and graphs show typical values.

Table 11-28. IDAC DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
	Resolution		–	–	8	bits
I _{OUT}	Output current at code = 255	Range = 2.04 mA, code = 255, V _{DDA} ≥ 2.7 V, R _{load} = 600 Ω	–	2.04	–	mA
		Range = 2.04 mA, high speed mode, code = 255, V _{DDA} ≤ 2.7 V, R _{load} = 300 Ω	–	2.04	–	mA
		Range = 255 μA, code = 255, R _{load} = 600 Ω	–	255	–	μA
		Range = 31.875 μA, code = 255, R _{load} = 600 Ω	–	31.875	–	μA
	Monotonicity		–	–	Yes	
E _{zs}	Zero scale error		–	0	±1	LSB
E _g	Gain error	Range = 2.04 mA, 25 °C	–	–	±2.5	%
		Range = 255 μA, 25 °C	–	–	±2.5	%
		Range = 31.875 μA, 25 °C	–	–	±3.5	%
TC _{Eg}	Temperature coefficient of gain error	Range = 2.04 mA	–	–	0.04	% / °C
		Range = 255 μA	–	–	0.04	% / °C
		Range = 31.875 μA	–	–	0.05	% / °C
INL	Integral nonlinearity	Sink mode, range = 255 μA, Codes 8 – 255, R _{load} = 2.4 kΩ, C _{load} = 15 pF	–	±0.9	±1	LSB
		Source mode, range = 255 μA, Codes 8 – 255, R _{load} = 2.4 kΩ, C _{load} = 15 pF	–	±1.2	±1.6	LSB
DNL	Differential nonlinearity	Sink mode, range = 255 μA, R _{load} = 2.4 kΩ, C _{load} = 15 pF	–	±0.3	±1	LSB
		Source mode, range = 255 μA, R _{load} = 2.4 kΩ, C _{load} = 15 pF	–	±0.3	±1	LSB
V _{compliance}	Dropout voltage, source or sink mode	Voltage headroom at max current, R _{LOAD} to V _{DDA} or R _{LOAD} to V _{SSA} , V _{DIFF} from V _{DDA}	1	–	–	V

Figure 11-40. IDAC Full Scale Error vs Temperature, Range = 255 μ A, Source Mode

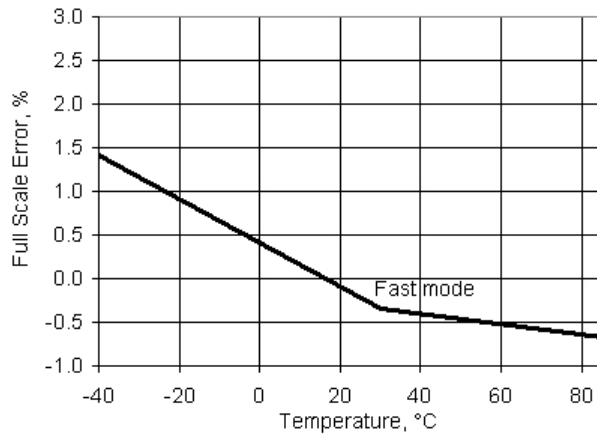


Figure 11-41. IDAC Full Scale Error vs Temperature, Range = 255 μ A, Sink Mode

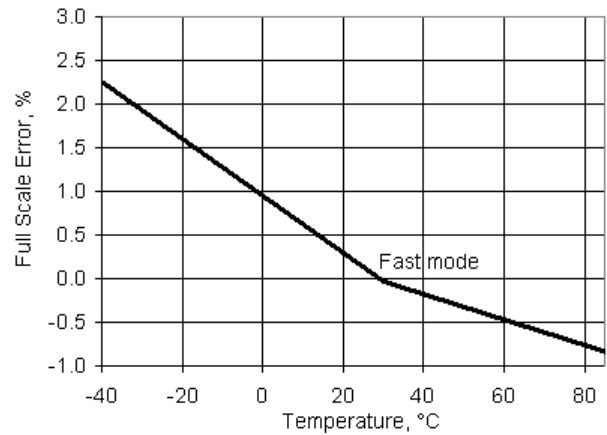


Figure 11-42. IDAC Operating Current vs Temperature, Range = 255 μ A, Code = 0, Source Mode

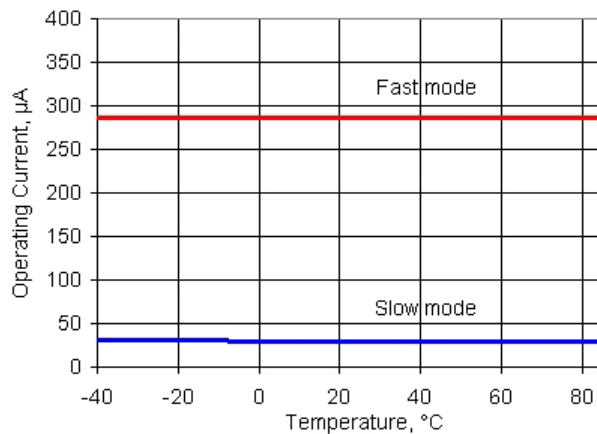


Figure 11-43. IDAC Operating Current vs Temperature, Range = 255 μ A, Code = 0, Sink Mode

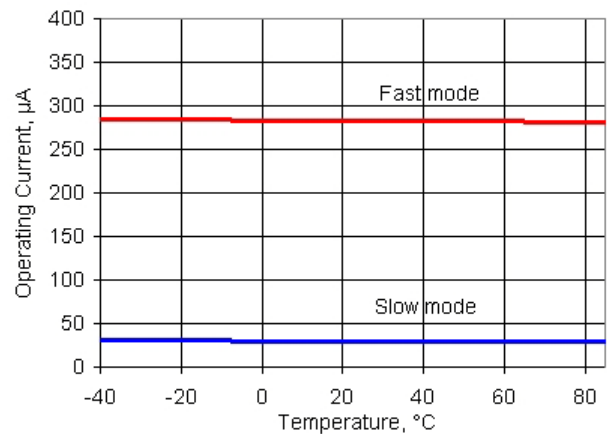


Table 11-29. IDAC AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
F_{DAC}	Update rate		–	–	8	Msp/s
T_{SETTLE}	Settling time to 0.5 LSB	Range = 31.875 μ A or 255 μ A, full scale transition, High speed mode, 600 Ω 15-pF load	–	–	125	ns
	Current noise	Range = 255 μ A, source mode, High speed mode, $V_{DDA} = 5$ V, 10 kHz	–	340	–	pA/sqrtHz

Figure 11-44. IDAC Step Response, Codes 0x40 - 0xC0, 255 μ A Mode, Source Mode, High speed mode, $V_{DDA} = 5$ V

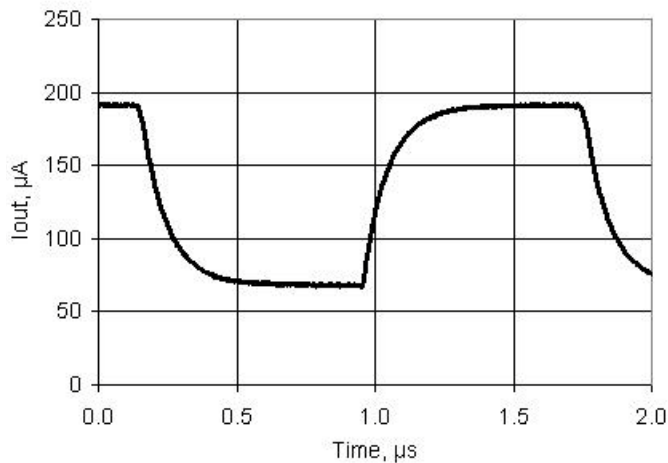


Figure 11-45. IDAC Glitch Response, Codes 0x7F - 0x80, 255 μ A Mode, Source Mode, High speed mode, $V_{DDA} = 5$ V

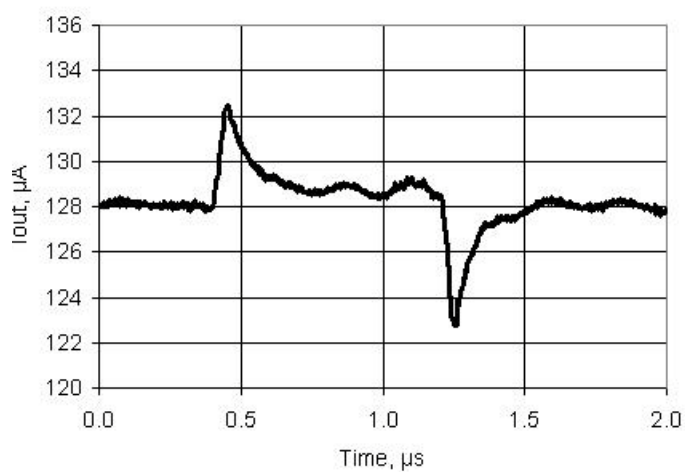


Figure 11-46. IDAC PSRR vs Frequency

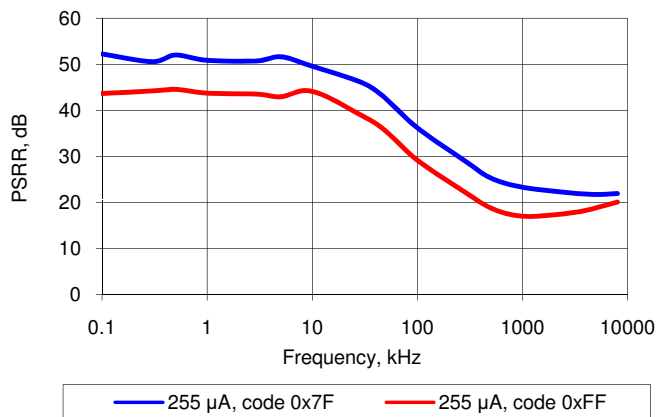


Figure 11-47. IDAC Current Noise, 255 μ A Mode, Source Mode, High speed mode, $V_{DDA} = 5$ V

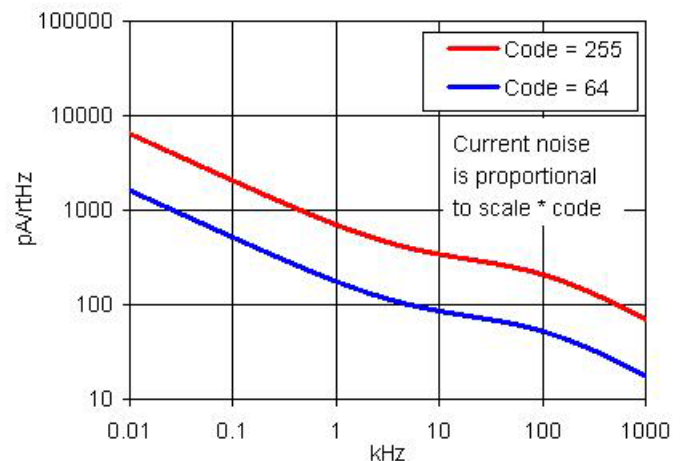


Table 11-37. PGA AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
BW1	–3 dB bandwidth	Power mode = high, gain = 1, input = 100 mV peak-to-peak	6.7	8	–	MHz
SR1	Slew rate	Power mode = high, gain = 1, 20% to 80%	3	–	–	V/μs
e _n	Input noise density	Power mode = high, V _{DDA} = 5 V, at 100 kHz	–	43	–	nV/sqrtHz

Figure 11-61. Bandwidth vs. Temperature, at Different Gain Settings, Power Mode = High

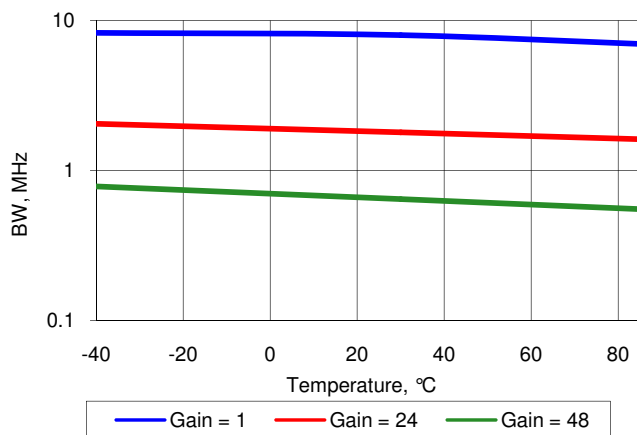
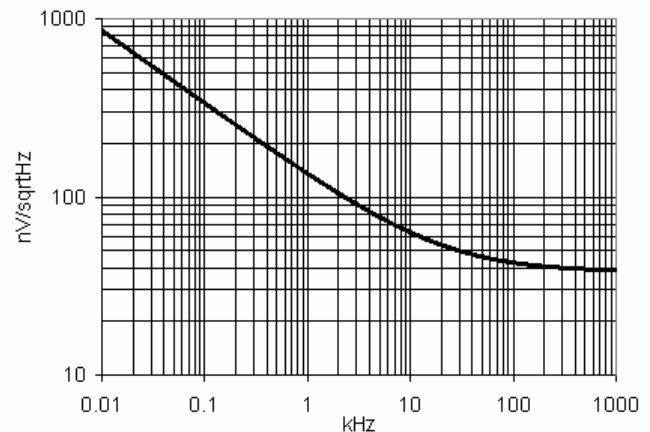


Figure 11-62. Noise vs. Frequency, V_{DDA} = 5 V, Power Mode = High



11.5.11 Temperature Sensor

Table 11-38. Temperature Sensor Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
	Temp sensor accuracy	Range: –40 °C to +85 °C	–	±5	–	°C

11.5.12 LCD Direct Drive

Table 11-39. LCD Direct Drive DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
I _{CC}	LCD system operating current	Device sleep mode with wakeup at 400-Hz rate to refresh LCDs, bus clock = 3 Mhz, V _{DDIO} = V _{DDA} = 3 V, 4 commons, 16 segments, 1/4 duty cycle, 50 Hz frame rate, no glass connected	–	38	–	μA
I _{CC SEG}	Current per segment driver	Strong drive mode	–	260	–	μA
V _{BIAS}	LCD bias range (V _{BIAS} refers to the main output voltage(V0) of LCD DAC)	V _{DDA} ≥ 3 V and V _{DDA} ≥ V _{BIAS}	2	–	5	V
	LCD bias step size	V _{DDA} ≥ 3 V and V _{DDA} ≥ V _{BIAS}	–	9.1 × V _{DDA}	–	mV
	LCD capacitance per segment/common driver	Drivers may be combined	–	500	5000	pF
	Long term segment offset		–	–	20	mV
I _{OUT}	Output drive current per segment driver)	V _{DDIO} = 5.5 V, strong drive mode	355	–	710	μA

Table 11-40. LCD Direct Drive AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
f _{LCD}	LCD frame rate		10	50	150	Hz

11.8.3 Interrupt Controller

Table 11-69. Interrupt Controller AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
	Delay from interrupt signal input to ISR code execution from ISR code	Includes worse case completion of longest instruction DIV with 6 cycles	–	–	25	Tcy CPU

11.8.4 JTAG Interface

Figure 11-68. JTAG Interface Timing

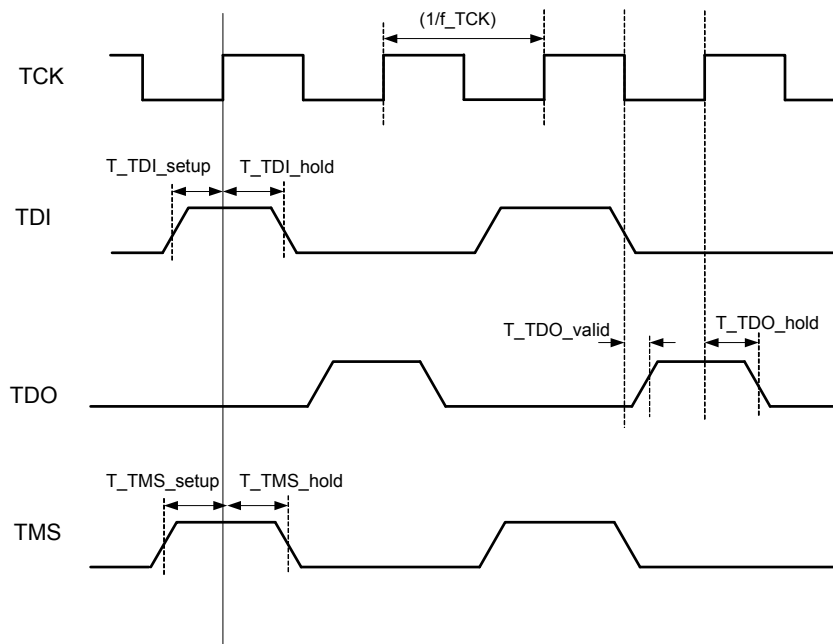


Table 11-70. JTAG Interface AC Specifications^[69]

Parameter	Description	Conditions	Min	Typ	Max	Units
f_TCK	TCK frequency	$3.3\text{ V} \leq V_{\text{DD}} \leq 5\text{ V}$	–	–	14 ^[70]	MHz
		$1.71\text{ V} \leq V_{\text{DD}} < 3.3\text{ V}$	–	–	7 ^[70]	MHz
T_TDI_setup	TDI setup before TCK high		$(T/10) - 5$	–	–	ns
T_TMS_setup	TMS setup before TCK high		T/4	–	–	
T_TDI_hold	TDI, TMS hold after TCK high	$T = 1/f_{\text{TCK}}$ max	T/4	–	–	
T_TDO_valid	TCK low to TDO valid	$T = 1/f_{\text{TCK}}$ max	–	–	2T/5	
T_TDO_hold	TDO hold after TCK high	$T = 1/f_{\text{TCK}}$ max	T/4	–	–	

Notes

69. Based on device characterization (Not production tested).
70. f_TCK must also be no more than 1/3 CPU clock frequency.

11.8.5 SWD Interface

Figure 11-69. SWD Interface Timing

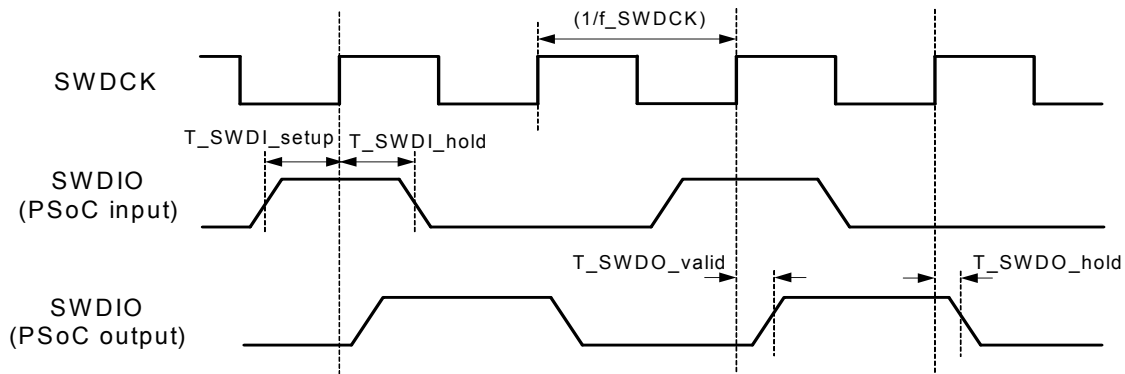


Table 11-71. SWD Interface AC Specifications^[71]

Parameter	Description	Conditions	Min	Typ	Max	Units
f_SWDCCK	SWDCLK frequency	$3.3\text{ V} \leq V_{DD} \leq 5\text{ V}$	–	–	14 ^[72]	MHz
		$1.71\text{ V} \leq V_{DD} < 3.3\text{ V}$	–	–	7 ^[72]	MHz
		$1.71\text{ V} \leq V_{DD} < 3.3\text{ V}$, SWD over USBIO pins	–	–	5.5 ^[72]	MHz
T_SWDI_setup	SWDIO input setup before SWDCK high	$T = 1/f_SWDCCK$ max	T/4	–	–	–
T_SWDI_hold	SWDIO input hold after SWDCK high	$T = 1/f_SWDCCK$ max	T/4	–	–	–
T_SWDO_valid	SWDCK high to SWDIO output	$T = 1/f_SWDCCK$ max	–	–	2T/5	–

11.8.6 SWV Interface

Table 11-72. SWV Interface AC Specifications^[71]

Parameter	Description	Conditions	Min	Typ	Max	Units
	SWV mode SWV bit rate		–	–	33	Mbit

Notes

71. Based on device characterization (Not production tested).

72. ff_SWDCCK must also be no more than 1/3 CPU clock frequency.

Figure 11-73. ILO Frequency Variation vs. Temperature

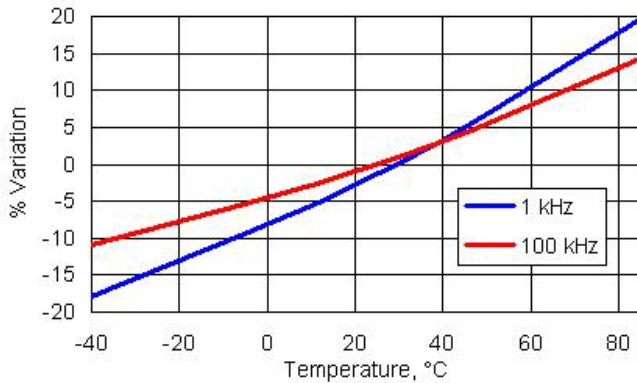
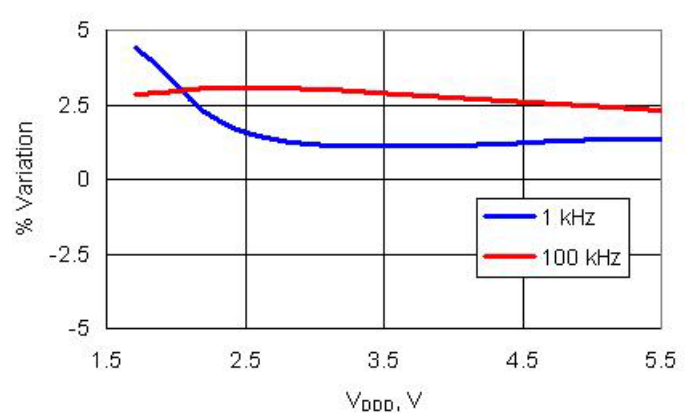


Figure 11-74. ILO Frequency Variation vs. V_{DD}



11.9.3 MHz External Crystal Oscillator

For more information on crystal or ceramic resonator selection for the MHzECO, refer to application note [AN54439: PSoC 3 and PSoC 5 External Oscillators](#).

Table 11-77. MHzECO DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
I _{CC}	Operating current ^[75]	13.56 MHz crystal	–	3.8	–	mA

Table 11-78. MHzECO AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
F	Crystal frequency range		4	–	25	MHz

11.9.4 kHz External Crystal Oscillator

Table 11-79. kHzECO DC Specifications^[75]

Parameter	Description	Conditions	Min	Typ	Max	Units
I _{CC}	Operating current	Low-power mode; CL = 6 pF	–	0.25	1.0	μA
DL	Drive level		–	–	1	μW

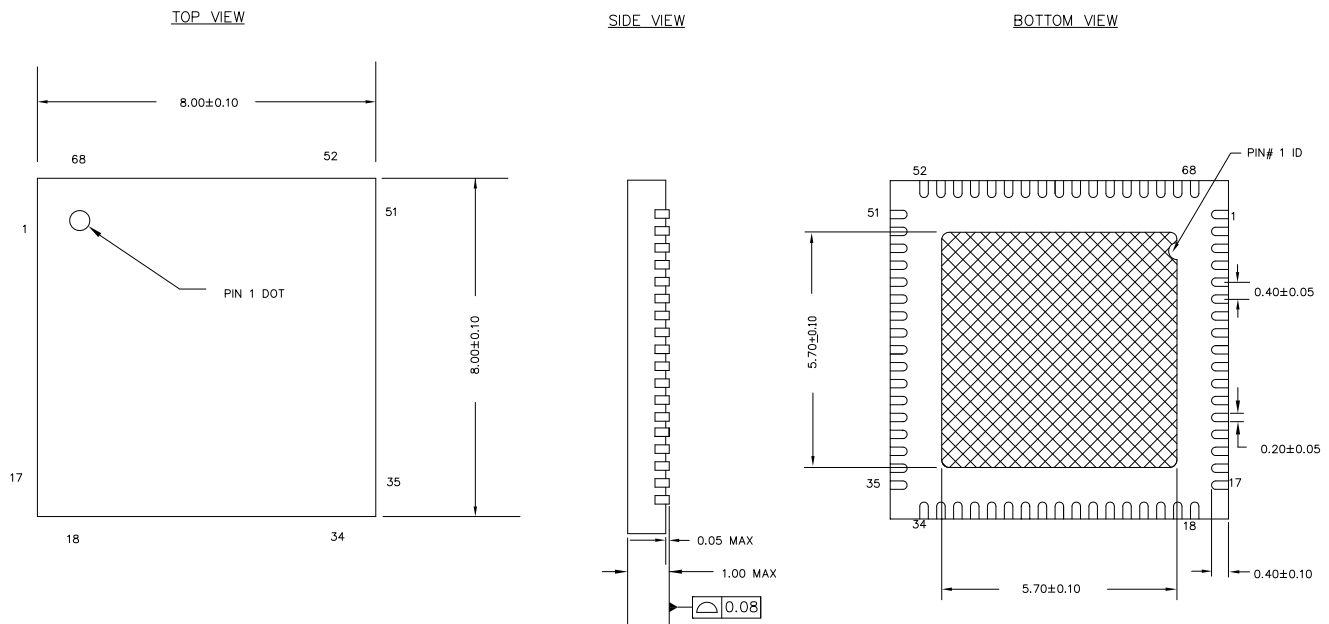
Table 11-80. kHzECO AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
F	Frequency		–	32.768	–	kHz
T _{ON}	Startup time	High-power mode	–	1	–	s

Note

75. Based on device characterization (Not production tested).

Figure 13-3. 68-pin QFN 8 × 8 with 0.4 mm Pitch Package Outline (Sawn Version)

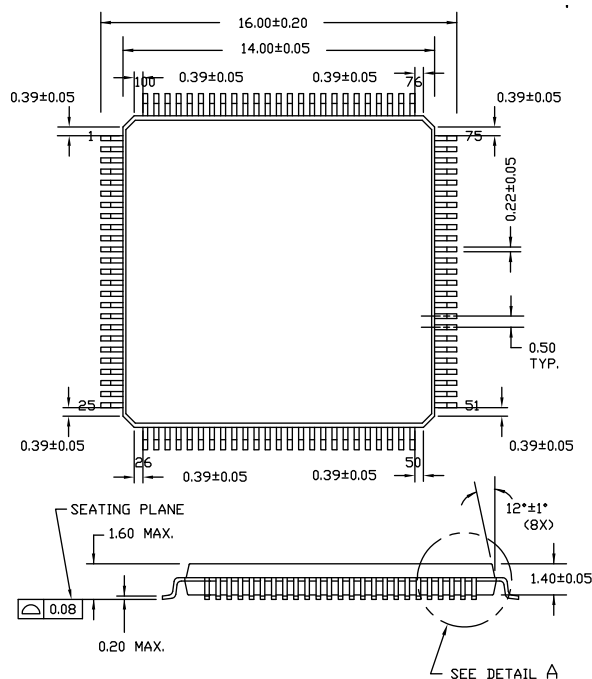


NOTES:

1. HATCH AREA IS SOLDERABLE EXPOSED METAL.
2. REFERENCE JEDEC#: MO-220
3. PACKAGE WEIGHT: 17 ± 2mg
4. ALL DIMENSIONS ARE IN MILLIMETERS

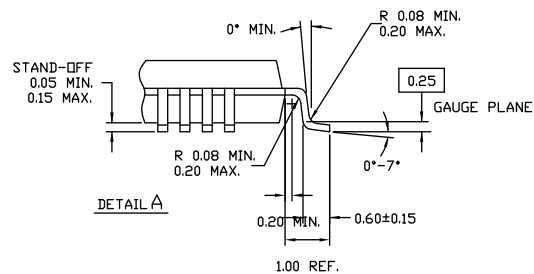
001-09618 *E

Figure 13-4. 100-pin TQFP (14 × 14 × 1.4 mm) Package Outline

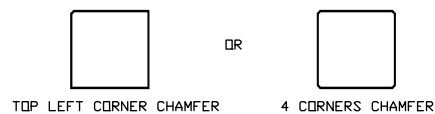


NOTE:

1. JEDEC STD REF MS-026
2. BODY LENGTH DIMENSION DOES NOT INCLUDE MOLD PROTRUSION/END FLASH
MOLD PROTRUSION/END FLASH SHALL NOT EXCEED 0.0098 in (0.25 mm) PER SIDE
BODY LENGTH DIMENSIONS ARE MAX PLASTIC BODY SIZE INCLUDING MOLD MISMATCH
3. DIMENSIONS IN MILLIMETERS



NOTE: PKG. CAN HAVE



51-85048 *J

Description Title: PSoC® 3: CY8C34 Family Datasheet Programmable System-on-Chip (PSoC®) (continued)
Document Number: 001-53304

Revision	ECN	Submission Date	Orig. of Change	Description of Change
*V	4708125	03/31/2015	MKEA	Added INL4 and DNL4 specs in VDAC DC Specifications . Updated Figure 6-11 . Added second note after Figure 6-4 . Added a reference to Fig 6-1 in Section 6.1.1 and Section 6.1.2 . Updated Section 6.2.2 . Added Section 7.8.1 . Updated Boost specifications.
*W	4807497	06/23/2015	MKEA	Added reference to code examples in More Information. Updated typ value of TWRITE from 2 to 10 in EEPROM AC specs table. Changed "Device supply for USB operation" to "Device supply (VDDD) for USB operation" in USB DC Specifications. Clarified power supply sequencing and margin for VDDA and VDDD. Updated Serial Wire Debug Interface with limitations of debugging on Port 15. Updated Section 11.7.5. Updated Delta-sigma ADC DC Specifications
*X	4932879	09/24/2015	MKEA	Changed the Regulator Output Capacitor min and max from "-" to 0.9 and 1.1, respectively. Added reference to AN54439 in Section 11.9.3. Added MHz ECO DC specs table. Removed references to IPOR rearm issues in Section 6.3.1.1. Table 6-1: Changed DSI Fmax to 33 MHz. Figure 6-1: Changed External I/O or DSI to 0-33 MHz. Table 11-10: Changed Fgpioin Max to 33 MHz. Table 11-12: Changed Fsioin Max to 33 MHz.
*Y	5322536	06/27/2016	MKEA	Updated More Information . Corrected typos in External Electrical Connections . Added links to CAD Libraries in Section 2.